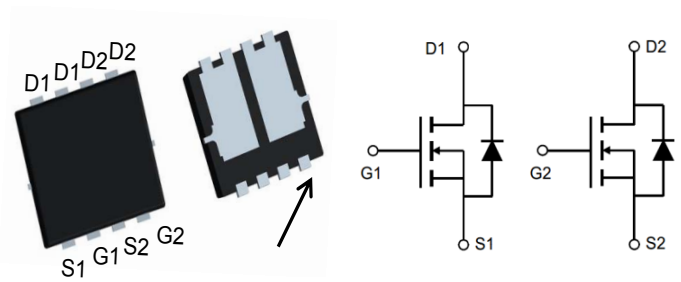


- ★ 100% EAS Guaranteed
- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology

Product Summary

BVDSS	RDSON	ID
30V	7mΩ	28A

PDFN3*3 Pin Configuration

Description

XPX308RX is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
XPX308RX	XPX308RX	PDFN3*3	---mm	---mm	5000

Table 1. Absolute Maximum Ratings (TA=25°C)

Symbol	Parameter	Value	Unit
V _{DS}	Drain-Source Voltage (V _{GS} =0V)	30	V
V _{GS}	Gate-Source Voltage (V _{DS} =0V)	±20	V
I _D	Drain Current-Continuous(T _c =25°C) (Note 1)	28	A
	Drain Current-Continuous(T _c =100°C)	17	A
IDM (pluse)	Drain Current-Continuous@ Current-Pulsed (Note 2)	40	A
P _D	Maximum Power Dissipation(T _c =25°C)	30.5	W
	Maximum Power Dissipation(T _c =100°C)	20	W
EAS	Avalanche energy (Note 3)	33	mJ
T _J , T _{STG}	Operating Junction and Storage Temperature Range	-55 To 150	°C

Table 2. Thermal Characteristic

Symbol	Parameter	Typ	Max	Unit
R _{θJC}	Thermal Resistance Junction-Case ¹	---	5.26	°C/W

Table 3. Electrical Characteristics (TA=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
On/Off States						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V I _D =250μA	30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V			1.0	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V, V _{DS} =0V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.2	1.6	2.1	V
g _{FS}	Forward Transconductance	V _{DS} =10V, I _D =15A		10		S
R _{DS(ON)}	Drain-Source On-State Resistance	V _{GS} =10V, I _D =20A		7.0	9.5	mΩ
		V _{GS} =4.5V, I _D =10A		12	16	mΩ
Dynamic Characteristics						
C _{iss}	Input Capacitance	V _{DS} =15V, V _{GS} =0V, F=1.0MHZ		830		PF
C _{oss}	Output Capacitance			142		pF
C _{rss}	Reverse Transfer Capacitance			119		pF
Switching Times						
t _{d(on)}	Turn-on Delay Time	V _{GS} =10V, V _{DS} =30V, R _G =3Ω I _D =2A		6		nS
t _r	Turn-on Rise Time			5		nS
t _{d(off)}	Turn-Off Delay Time			25		nS
t _f	Turn-Off Fall Time			7		nS
Q _g	Total Gate Charge	V _{GS} =10V, V _{DS} =15V, I _D =20A		19		nC
Q _{gs}	Gate-Source Charge			6.3		nC
Q _{gd}	Gate-Drain Charge			4.5		nC
Source-Drain Diode Characteristics						
I _S		V _G =V _D =0V , Force Current			25	A
V _{SD}	Forward on Voltage	V _{GS} =0V, I _S =30A			1.2	V
t _{rr}	Reverse Recovery Time	I _F =30A dI/ dt=100A/ μs ,		7		ns
Q _{rr}	Reverse Recovery Charge				6.3	

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. V_{DD}=50V, V_{GS}=10V, L=0.1mH, I_{AS}=48A., R_G=25Ω, Starting T_J=25°C.
3. The data tested by pulsed , pulse width ≅ 300us , duty cycle ≅ 2%.
4. Essentially independent of operating temperature.

Typical Performance Characteristics

Figure 1: Output Characteristics

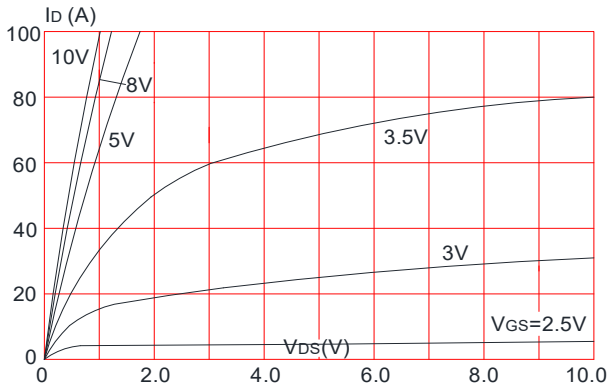


Figure 2: Typical Transfer Characteristics

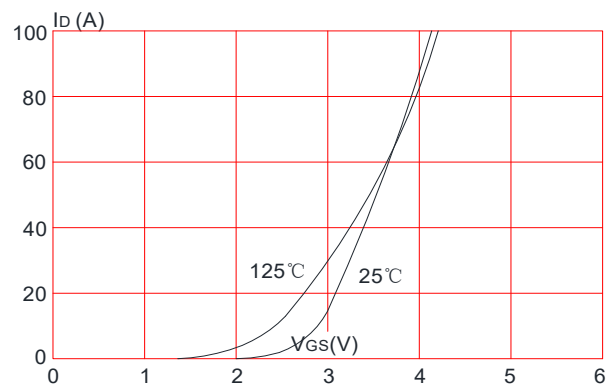


Figure 3: On-resistance vs. Drain Current

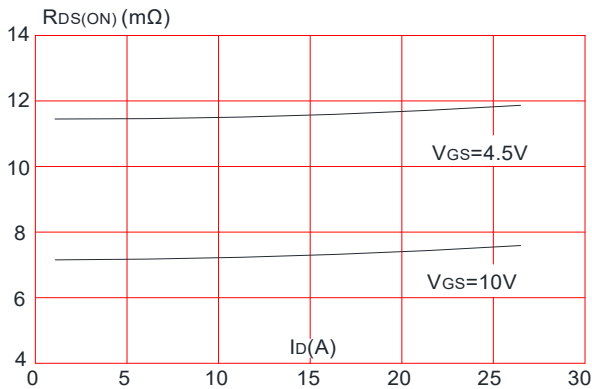


Figure 4: Body Diode Characteristics

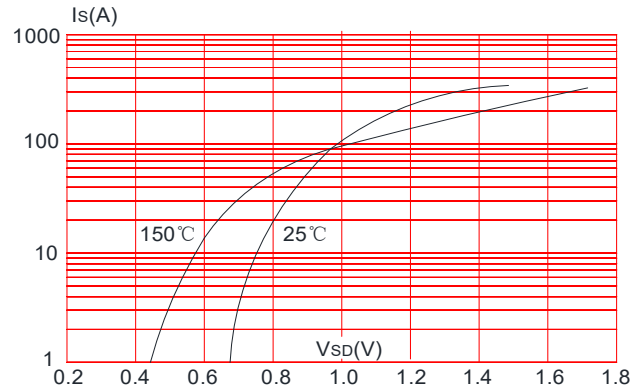


Figure 5: Gate Charge Characteristics

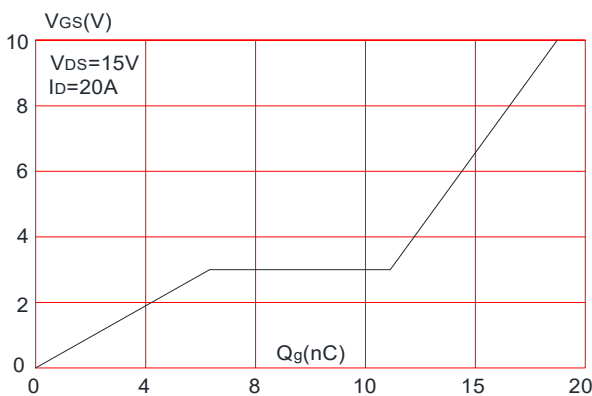
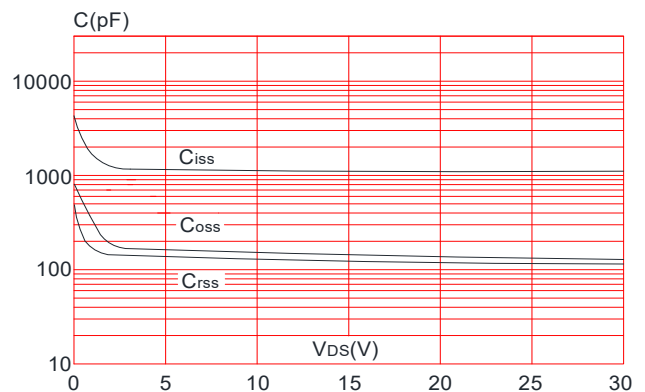


Figure 6: Capacitance Characteristics



0

Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

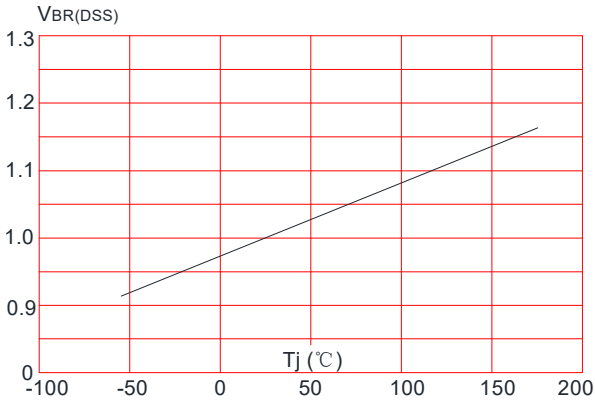


Figure 8: Normalized on Resistance vs. Junction Temperature

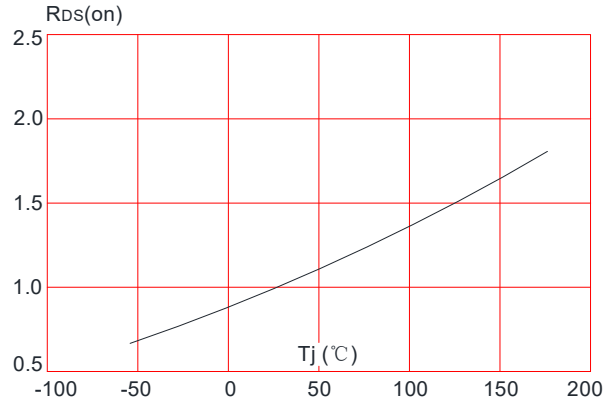


Figure 9: Maximum Safe Operating Area

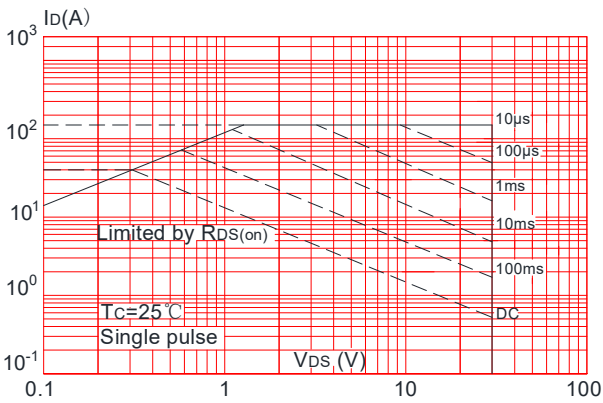
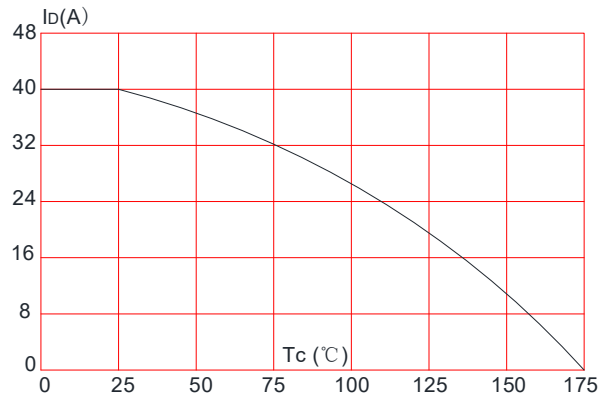
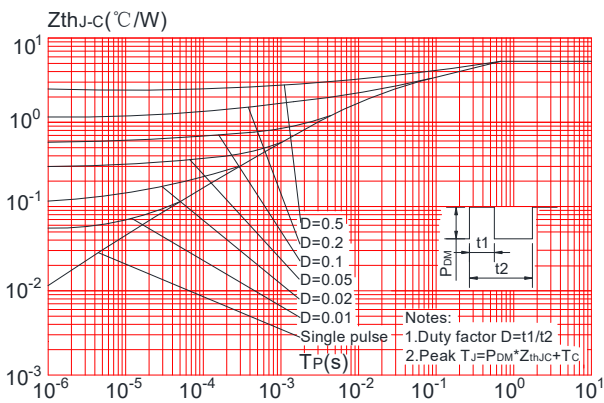


Figure 10: Maximum Continuous Drain Current vs. Case Temperature



Maximum Effective Transient Thermal Impedance, Junction-to-Case



Test Circuit

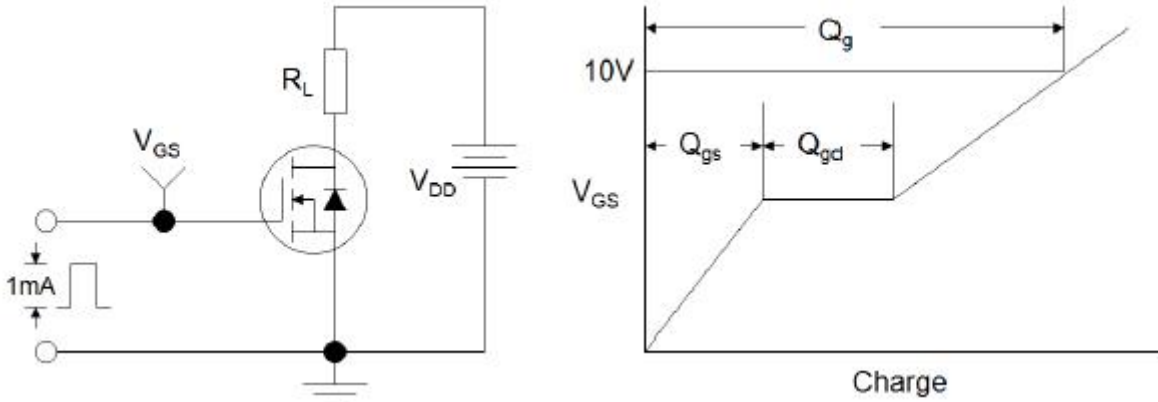


Figure1:Gate Charge Test Circuit & Waveform

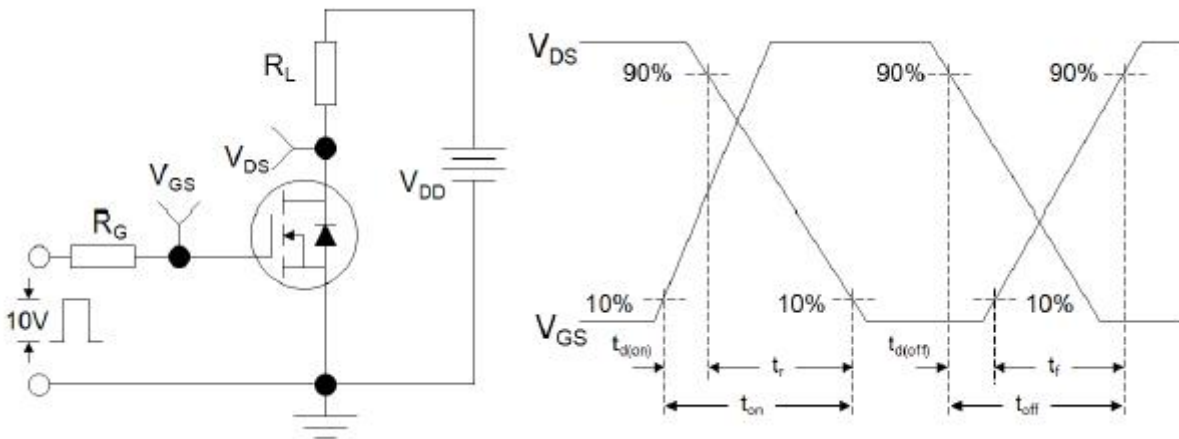


Figure 2: Resistive Switching Test Circuit & Waveforms

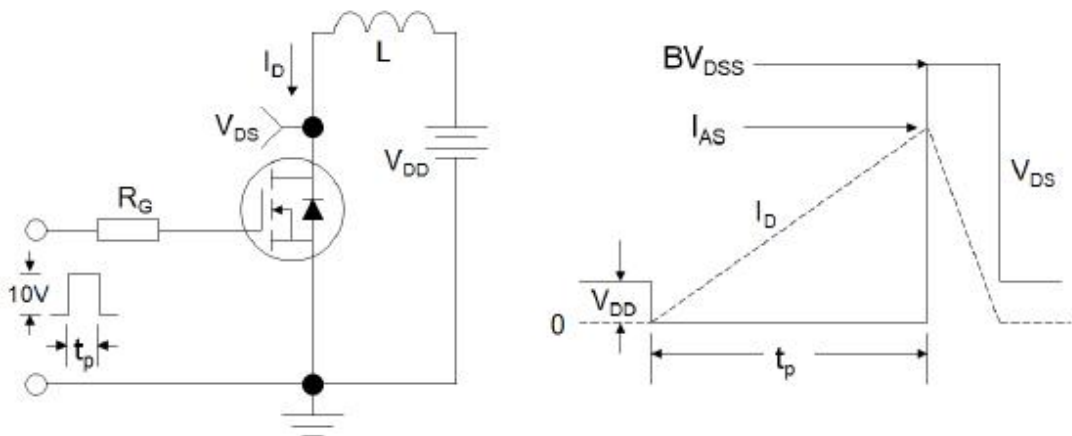
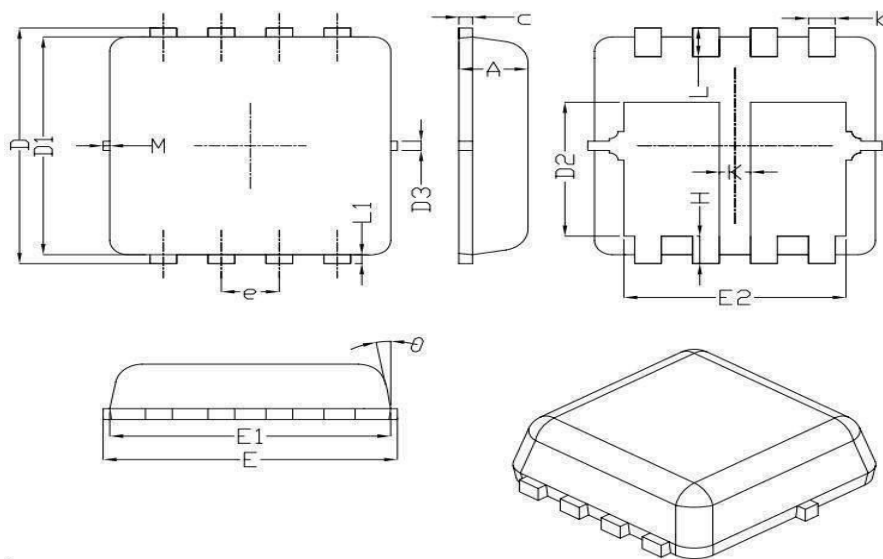


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

•Dimensions (PDFN3.3×3.3)


Symbol	Dimensions (unit: mm)		
	Min	Typ	Max
A	0.70	0.75	0.80
b	0.25	0.30	0.35
c	0.10	0.15	0.25
D	3.25	3.35	3.45
D1	3.00	3.10	3.20
D2	1.78	1.88	1.98
D3	--	0.13	--
E	3.20	3.30	3.40
E1	3.00	3.15	3.20
E2	2.39	2.49	2.59
e	0.65 BSC		
H	0.30	0.39	0.50
L	0.30	0.40	0.50
L1	--	0.13	--
K	0.30	--	--
θ	--	10°	12°
M	*	*	0.15

* Not Specified

Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	245°C ±5°C	5sec ±1 sec
Pb-Free device	260°C +0/-5°C	5sec ±1 sec



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

Attention:

- Any and all XPX power products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your XPX power representative nearest you before using any XPX power products described or contained herein in such applications.
- XPX power assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all XPX power products described or contained herein.
- Specifications of any and all XPX power products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- XPX power Semiconductor CO.,LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all XPX power products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of XPX power Semiconductor CO.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only ; it is not guaranteed for volume production. XPX power believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/ technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the XPX power product that you intend to use.
- This catalog provides information as of Sep.2019. Specifications and information herein are subject to change without notice.